



Jihan Joo

Attorney

Washington, DC

jjoo@bannerwitcoff.com

Main: 202-824-3000

Fax: 202-824-3001

Jihan practices patent prosecution and strategic patent counseling in the computer and electrical industries. Jihan has prepared and prosecuted numerous patent applications for Fortune 100 companies across a wide range of technologies including user interface, networking, storage, cloud computing, virtual machines, mobile communications, smartphones, smart TVs, cryptography, semiconductors, and teleconferencing.

Before entering into the practice of patent law, Jihan worked as a software engineer in the Semiconductor Division at Samsung Electronics in South Korea. As a software engineer, he helped write firmware for solid-state drive (SSD) controllers. While he was attending the George Washington University Law School, Jihan served as a staff member on the American Intellectual Property Law Association (AIPLA) Journal and interned for the Honorable Jimmie V. Reyna of the U.S. Court of Appeals for the Federal Circuit.

Jihan speaks fluent Korean and served as one of the principal editors of a premier Korean-language intellectual property law blog, HelloIPLaw.com, to which he has contributed more than 25 IP-related articles and case analyses.

Jihan is a member of the Maryland Bar and the District of Columbia Bar, and is admitted to practice before the United States Patent and Trademark Office.

Education

Seoul National University
2008, B.S., Electrical and Computer Engineering

George Washington University Law School
2012, J.D.

Admissions

Bar Admissions

District of Columbia
2013, Maryland

Court Admissions

District of Columbia Court of Appeals
Superior Court of the District of Columbia
U.S. Patent and Trademark Office

Practices

Patent Prosecution

Industries

Electrical + Computer Technologies

Recent News + Events + Related Publications

NEWS - 01.02.26

PTAB Highlights | Takeaways from Recent Decisions in Post-Issuance Proceedings

NEWS - 10.03.24

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